

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: HAMAMATSU, et al.

Filed: December 2, 2003

For: METHOD FOR INSPECTING DEFECT AND APPARATUS FOR  
INSPECTING DEFECT

**CLAIM FOR PRIORITY**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

December 2, 2003

Sir:


Under the provisions of 35 USC §119 AND 37 CFR § 1.55, Applicants hereby claim the right of priority based on Patent Application No. 2002-349357 filed in Japan on December 2, 2002.

Under the provisions of 35 USC §119, Applicants hereby claim the right of priority based on Patent Application No. 2002-347134 filed in Japan on November 29, 2002.

A certified copy of 2002-347134 was filed in parent application U.S. Serial Number \_\_\_\_\_, filed November 28, 2003, by Hamamatsu et al, entitled "Inspection Method and Inspection Apparatus".

Respectfully submitted,

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